

<b>Notice of References Cited</b>	Application/Control No. 10/566,686		Applicant(s)/Patent Under Reexamination LIU ET AL.	
	Examiner JONATHAN C. LANGMAN		Art Unit 1784	Page 1 of 2

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,633,194	05-1997	Selvakumar et al.	117/103
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kanel et al., "Ballistic-Electron-Emission spectroscopy", Applied Phsyics A, Vol. 72, (2001), pgs S227-S232.
	V	Meyer et al., "Electron and hole Focusing in CoSi2/Si(111) Observed by ballistic Electron emission Microscopy", Physical Review Letters, Col. 85, 2000, pgs 1520-1523.
	W	Seto et al., "Si/SiGe resonant cavity photodiodes for optical storage applications", Applied Physics Letters, Vol. 72, 1998, pg 1550-1552.
	X	Kubler et al., "Si adatom surface migration biasing by elastic strain gradients during capping of Ge or Si1-xGex hut islands", Applied Physics letters, Col. 73, 1998, pgs 1053-1055.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/566,686	Applicant(s)/Patent Under Reexamination LIU ET AL.	
	Examiner JONATHAN C. LANGMAN	Art Unit 1784	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sutter et al., "Embedding of Nanoscale 3D SiGe islands in a Si Matrix", Physical Review Letters, Col. 81, 1998, pgs 3471-3474.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.